

DYNAMICAL THEORY OF COPLANAR N -BEAM
X-RAY DIFFRACTION IN MULTILAYERED
STRUCTURES

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S u m m a r y

A new approach to calculating the coplanar N -beam X-ray dynamical diffraction in multilayered structures has been presented. The theory produces adequate results in the wide range of angles, including the grazing incidence. It can be applied to calculate the reflected beam and diffraction by thick layers. It can also be used to take into account practically any number of reciprocal lattice sites that participate in diffraction.